

2018 IEEE AUTOTESTCON

**National Harbor, Maryland, USA
17 – 20 September 2018**



**IEEE Catalog Number: CFP18AUT-POD
ISBN: 978-1-5386-5224-4**

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IEEE Catalog Number:	CFP18AUT-POD
ISBN (Print-On-Demand):	978-1-5386-5224-4
ISBN (Online):	978-1-5386-5223-7
ISSN:	1088-7725

Additional Copies of This Publication Are Available From:

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TABLE OF CONTENTS

GENERAL CHAIR'S MESSAGE	xiii
FROM THE TECHNICAL CHAIR.....	xiv
KEYNOTE SPEAKER	xv
IEEE AUTOTESTCON 2018 COMMITTEE	xvi
IEEE AUTOTESTCON BOARD OF DIRECTORS	xvi
IEEE AUTOTESTCON 2018 SPONSORS	xvii
IEEE AUTOTESTCON 2018 Promotional Partners	xviii
AWARDS.....	xx
MASTER SCHEDULE.....	xxii
TUTORIAL PROGRAM.....	xxiii
TECHNICAL SESSIONS SCHEDULE.....	xxv
IEEE AUTOTESTCON 2019 Call for Papers	xxvi

Tuesday, September 18

1D1: ATE Next Generation Test Systems

15:00 - 17:00

Room: Riverview 1

Session Chair: Dean Matsuura (Teradyne Inc., USA)

Single-Event Effects Characterization using a Single Photon Absorption Laser1

Adam Watkins (Los Alamos National Laboratory, USA)

Heather Quinn (Los Alamos National Laboratory, USA)

Test Challenges of Multi-Gigabit Serial Buses5

Michael Fluet (Teradyne, Inc., USA)

Pavel Gilenberg (Teradyne, Inc., USA)

Next Generation Armament Test Solutions for the Flightline.....12

Loofie Gutterman (Geotest - Marvin Test Systems, USA)

1D2: Boundary Scan and Built-In-Test

15:00 - 17:00

Room: Riverview 2

Session Chair: Russell A Shannon (NAVAIR, USA)

JTAG/Boundary Scan for Built-In Test.....16

Alan Sguigna (ASSET InterTech, Inc., USA)

The Increasing Importance of Utilizing Non-Intrusive Board Test Technologies for Printed Circuit Board Defect Coverage19

Michael Johnson (ASSET InterTech, Inc., USA)

Boundary-scan, a cradle-to-grave test, programming and maintenance solution that stands the test of time24

Peter van den Eijnden (JTAG Technologies, The Netherlands)

Anthony Sparks (JTAG Technologies, USA)

IEEE 1687 Compliant Ecosystem for Embedded Instrumentation Access and In-Field Health Monitoring28

Anton Tsertov (Testonica Lab, Estonia)

Konstantin Shibin (Testonica Lab, Estonia)

Artur Jutman (Testonica Lab, Estonia)

Sergei Devadze (Testonica Lab OÜ, Estonia)

1D3: Maintenance Repair & Overhaul

15:00 – 17:00

Room: Riverview 5

Session Chair: David R Carey (Lockheed Martin & Wilkes University, USA)

Platform Mis-Diagnoses, NEOFs, and the ATE Perspective37

Patrick Curry (PD TMDE - Army, USA)

Data Collection for Disconnected Diagnostics in a Net-Centric Environment42

Josselyn Webb (USMC, USA)

Managing Factory Test Content under a Risk Management Framework.....51

Randal Bailey (BAE SYSTEMS, USA)

Future of PCB Diagnostics and Trouble-Shooting59
Sreenivasan Rathina Sabapathi (IEEE & Qmax Test Equipments Pvt Ltd, India)

1D4: Cyber Security

15:00 - 17:00

Room: Riverview 4

Session Chair: Christopher J Sparr (NAVAIR, USA)

Information Assurance in modern ATE.....69

Joe Headrick (Lockheed Martin, USA)

Paul Rajcok (NAVAIR, USA)

Anne Dlugosz (NAVAIR, USA)

Virtual Applications Reduce Cyber Attack Surface for Test Program Sets and Station Software73

Christopher P Heagney (US Naval Air Systems Command, USA)

Lance Walker (US Naval Air Systems Command, USA)

Measuring and Assessing the Cybersecurity Risk of Support Equipment to Complex Systems81

Christopher J Guerra (Southwest Research Institute, USA)

Christopher E Camargo (Southwest Research Institute, USA)

Wednesday, September 19

2B1: Developments in Instrumentation and Measurement I

10:00 - 12:00

Room: Riverview 1

Session Chair: Alberto Tungcab (NAVAIR, USA)

Choosing the Right Platform for Switching: PXI, USB or LXI?89

Robert A Stasonis (Pickering Interfaces, Inc., USA)

Keith Moore (Pickering Interfaces Ltd., United Kingdom (Great Britain))

Challenges of Replacing Legacy Analog Instrumentation During TPS Rehost Projects92

Yonet A Eracar (Teradyne, Inc., USA)

Thomas Jacobs (Teradyne, Inc., USA)

Parallel mixed signal testing as an embedded instrument97

Robert Spinner (Advanced Testing Technologies, Inc. & ATTI, USA)

William Biagiotti (Advanced Testing Technologies, Inc. & ATTI, USA)

James McKenna (Advanced Testing Technologies, Inc. & ATTI, USA)

William Leippe (Advanced Testing Technologies, Inc. & ATTI, USA)

An Algorithm for Selecting Sampling Rate in Arbitrary Waveform Generator102

Yindong Xiao (University of Electronic Science and Technology of China, P.R. China)

Yu Chen (University of Electronic Science and Technology of China, P.R. China)

Ke Liu (University of Electronic Science and Technology of China, P.R. China)

Guangkun Guo (University of Electronic Science and Technology of China, P.R. China)

Wenhao Zhao (University of Electronic Science and Technology of China, P.R. China)

Lei Huang (University of Electronic Science and Technology of China, P.R. China)

2B2: Software Standards

10:00-12:00

Room: Riverview 2

Session Chair: Teresa P Lopes (Teradyne, Inc., USA)

Best Practices for Describing Digital Serial Buses and Bus Test Operations Using IEEE 1671 ATML and IEEE 1641 Signal and Test Definition108

Ion A Neag (Reston Software, LLC, USA)

Chris C Gorringe (SPHEREA Technology Ltd., United Kingdom (Great Britain))

Model-Based Design Patterns for describing Test Station and Resource Capabilities117

Chris C Gorringe (SPHEREA Technology Ltd., United Kingdom (Great Britain))

Ion A Neag (Reston Software, LLC, USA)

An Investigation of Current and Emerging Standards to Support a Framework for Prognostics and Health Management in Automatic Test Systems124

John W. Sheppard (Montana State University, USA)

Joseph DeBruycker (Montana State University, USA)

A Signals Intelligence Approach to Automated Assessment of ATE Capabilities131

R. Glenn Wright (GMATEK, Inc., USA)

Larry V. Kirkland (WesTest Engineering, USA)

2B3: Fault Diagnostics and Health Monitoring of Electrical Cables I

10:00-12:00

Room: Riverview 5

Session Chair: Moussa Kafal (CEA, LIST, France)

Spread Spectrum Time Domain Reflectometry for Complex Impedances: Application to PV Arrays 139

Cynthia Furse (University of Utah & LiveWire Innovation, USA)

Naveen Kumar (University of Utah, USA)

Evan Benoit (University of Utah, USA)

Mashad Saleh (University of Utah, USA)

Josiah Lacombe (University of Utah, USA)

Michael Scarpulla (University of Utah, USA)

Joel B Harley (University of Florida, USA)

Samuel Kingston (University of Utah, USA)

Brent Waddoups (LiveWire Innovation, LLC, USA)

Chris Deline (NREL, USA)

A Novel Compressive Sampling Approach for Detecting Hard Faults in Complex Wire Networks 143

Tzila Ajamian (CEA, France)

Saïd Moussaoui (LS2N, France)

Antoine Dupret (CEA/LETI-MINATEC, France)

A Non Destructive Reflectometry Based Method for the Location and Characterization of Incipient Faults in Complex Unknown Wire Networks 147

Moussa Kafal (CEA, LIST, France)

Fatme Mustapha (CEA, LIST, France)

Wafa Ben Hassen (CEA LIST, France)

Jaume Benoit (CEA, LIST, France)

Prognostics of Electrical Wiring Interconnect Systems (EWIS) Using Precise Automated Testing at Phase Maintenance 155

Christopher T Teal (Eclipse International Corporation, USA)

C. Alan Ferguson (Chairman of the Board & Eclipse International Corporation, USA)

2B4: Test Requirements Definition and Verification

10:00-12:00

Room: Riverview 4

Session Chair: Randall L Marion (The Boeing Company, USA)

Lessons Learned in Utilizing the SETR Process in the Procurement of TPSs on the CASS Family of Testers 160

Neil McLellan (Fleet Readiness Center Southeast & Navy, USA)

Arthur R Shilling, Jr (NAVAIR & Fleet Readiness Center Southeast, USA)

Challenges and Solutions for Testing Modern Optically Networked Weapon Systems 165

Tony Erwin (Teradyne, USA)

Test Station Validation / Certification in a Production Environment 170

George Isabella (Data Device Corporation, USA)

A Self-Calibrating, Erroneous Measurement-Preventing Production Test System for Military Slip Rings 173

Safa Şengezer (Aselsan Inc., Turkey)

Volkan Özdemir (ASELSAN Inc., Turkey)

Fatih Demir (ASELSAN Inc., Turkey)

2B5: PCB Diagnostics and Repair

10:00-12:00

Room: Eastern Shore 1

Session Chair: Robert Hoover (Teradyne, Inc., USA)

A System for Detecting Failed Electronics Using Acoustics.....178

Russell A Shannon (NAVAIR, USA)

Gregory Zucaro (US Navy & Naval Air Warfare Center - Aircraft Division, USA)

Justin Tallent (NAVAIR, USA)

Vontrelle Collins (NAVAIR, USA)

John Carswell, III (Department of the Navy, USA)

Alternative Multivariate Methods for State Estimation, Anomaly Detection, and Prognostics.....183

Ferenc Szidarovszky (Ridgetop Group, Inc., USA)

In-Field Detection of Degradation on PCB Assembly High-Speed Buses.....188

Sergei Odintsov (Testonica Lab, Estonia)

2C1: Developments in Instrumentation and Measurement II

13:30 - 15:00

Room: Riverview 1

Session Chair: Lyle Beck (NAVAIR, USA)

Fibre Channel Time Synchronization for Automated Testing194

Laura Catrine (Avionics Interface Technologies & Teradyne, USA)

'Small Data' Anomaly Detection for Unmanned Systems197

Aaron Radke (Metron Inc., USA)

Research on fast and intelligent calibration method based on automatic test system.....204

Fu Zaiming (University of Electronic Science and Technology of China, P.R. China)

Ren Nan (University of Electronic Science and Technology of China, P.R. China)

Ke Liu (University of Electronic Science and Technology of China, P.R. China)

Yijiu Zhao (University of Electronic Science and Technology of China, P.R. China)

2C2:Test Program Set Development

13:30-15:00

Room: Riverview 2

Session Chair: Timothy W Davis (NAVAIR & Fleet Readiness Center Southeast, USA)

Sorting out Integration Snags by Using Actual Automatic Test Equipment for Simulations209

Larry V. Kirkland (WesTest Engineering, USA)

Dave Jensen (WesTest Engineering Corporation, USA)

Calvin Carlson (WesTest Engineering Corporation, USA)

A New Approach to TPS Rehost Using a Modular Token Mapping System.....216

Roy Albertson, IV (USAF, USA)

Thomas Carlisle (USAF, USA)

Corris Stewart (USAF, USA)

Viet Nguyen (USAF, USA)

C. Justin Smith (USAF, USA)

Phuong Nguyen (USAF, USA)

Jarrod Haning (USAF, USA)

Geoffrey Dolinger (USAF, USA)

Roy Albertson, IV (USAF, USA)

Innovative Support Alternatives to Reduce Overall Weapon System Life Cycle Cost	226
Randall L Marion (The Boeing Company, USA)	
2C3: Fault Diagnostics and Health Monitoring of Electrical Cables II	
13:30-15:00	
Room: Riverview 5	
Session Chair: Moussa Kafal (CEA, LIST, France)	
Binary time domain reflectometry: a simpler and more efficient way of diagnosing defects in wired networks.....	231
Fabrice Auzanneau (CEA LIST, France)	
On the Implementation of Embedded Communication over Reflectometry-oriented Hardware for Distributed Diagnosis in Complex Wiring Networks	239
Esteban Cabanillas (CEA, LIST, France)	
Moussa Kafal (CEA, LIST, France)	
Wafa Ben Hassen (CEA LIST, France)	
Time Reversal Applied to Multi-Carrier Reflectometry for On-line Diagnosis in Complex Wiring Systems	245
Wafa Ben Hassen (CEA LIST, France)	
Moussa Kafal (CEA, LIST, France)	
Esteban Cabanillas (CEA, LIST, France)	
2C5: FPGA and Embedded Instrumentation	
13:30-15:00	
Room: Eastern Shore 1	
Session Chair: Joe Cuccaro (US Army, USA)	
Leveraging Industry Standards for User Programmable FPGA Instrumentation	252
Michael J Dewey (Marvin Test Solutions, USA)	
Portable Test System for Jet Engines through FPGA Technology	257
Henrique Kubinhetz Martim Ramos (IFSP - Federal Institute of São Paulo, Campus São Paulo, Brazil)	
Mariana Roskosz Gonzalez (IFSP - Federal Institute of São Paulo. Campus São Paulo, Brazil)	
Rafael Mello de Mendonça (IFSP - Federal Institute of São Paulo, Campus São Paulo, Brazil)	
Gustavo Caldeira Colombo (IFSP - Federal Institute of São Paulo, Campus São Paulo, Brazil)	
David Rodrigo Gonçalves Ribeiro (Brazilian Air Force, Brazil); Alexandre Brincalepe Campo (IFSP - Federal Institute of São Paulo, Campus São Paulo, Brazil)	
Radar Antenna Test In the Loop Far-Field Measurements.....	265
Atacan Özkan (ASELSAN, Turkey)	
2D1: Vehicle Test	
15:30 - 17:30	
Room: Riverview 1	
Session Chair: Sunil Dixit (NGC, USA)	
The Millimeter Wave (mmW) radar characterization, testing verification challenges and opportunities ...	269
Uma S. Jha (Space and Airborne Systems, Raytheon Company, El Segundo, California, USA)	

VICTORY: A New Approach to Automated Vehicle Testing	274
Travis Thompson (Southwest Research Institute, USA)	
Kase Saylor (Southwest Research Institute, USA)	
System Level Test Automation In UAV Development	278
Abdullah Sinan Yildirim (Turkish Aerospace Industries (TAI), Turkey)	
Edip Berker (Turkish Aerospace Industries, Turkey)	
Mustafa Erman Kayakesen (Turkish Aerospace Industries, Turkey)	
2D2: Test Program Set Development and Software Testing	
15:30-17:30	
Room: Riverview 2	
Session Chair: Scott K Kautzmann (US Army ARDEC, USA)	
System Level Health and Environmental Monitoring for Automatic Test Equipment	284
James Orlet (The Boeing Company, USA)	
Integrated technologies fulfill the potential of parallel mixed signal testing	288
Robert Spinner (Advanced Testing Technologies, Inc. & ATTI, USA)	
William Biagiotti (Advanced Testing Technologies, Inc. & ATTI, USA)	
James McKenna (Advanced Testing Technologies, Inc. & ATTI, USA)	
William Leippe (Advanced Testing Technologies, Inc. & ATTI, USA)	
Automated Testing Business Impact	293
Joseph Bosas, Jr (Honeywell Federal Manufacturing and Technology, USA)	
2D3: Health Monitoring & Diagnostics	
15:30-17:30	
Room: Riverview 5	
Session Chair: John W. Sheppard (Montana State University, USA)	
Techniques to Solve TPS Performance Weaknesses	297
Larry V. Kirkland (WesTest Engineering, USA)	
Dave Jensen (WesTest Engineering Corporation, USA)	
Calvin Carlson (WesTest Engineering Corporation, USA)	
R. Glenn Wright (GMATEK, Inc., USA)	
Platform Independent Network-Based Health Monitoring & Diagnostic Solution for Urban Security Surveillance System and License Plate Recognition System	304
Çağlar Mustafa Güldiken (ASELSAN INC., Turkey)	
Onder Unver (ASELSAN INC., Turkey)	
A Novel Degradation prediction for Analog Circuits using particle filter	311
Yang Yu (Harbin Institute of Technology, P.R. China)	
Yueming Jiang (Harbin Institute of Technology, P.R. China)	
Junyan Liu (Harbin Institute of Technology, P.R. China)	
Zhiming Yang (Harbin Institute of Technology, P.R. China)	
Xiyuan Peng (Harbin Institute of Technology, P.R. China)	

2D4: Test & Support Management I

15:30-17:30

Room: Riverview 4

Session Chair: Mark Elo (Tekronix, USA)

Using a Common Tester Architecture: A Case Study320

Eric A Bean (National Nuclear Security Administration's Kansas City National Security Campus & Honeywell, USA)

Execution of a Test Program Like a Military Campaign324

Vi Weaver (Raytheon Missile Systems, USA)

Juan Ramos (Raytheon Missile Systems, USA)

Edward Ly (Raytheon Missile Systems, USA)

Juan Ortiz (Raytheon Missile Systems, USA)

**SUPPORTING MULTIPLE RUNTIME ENGINES ON A COMMON AND SCALABLE AUTOMATIC TEST
EQUIPMENT (ATE) FRAMEWORK334**

Steve Wegener (The Boeing Company, USA)

Thursday, September 20

3B1: Burn in Test

10:30 - 12:00

Room: Baltimore 2

Session Chair: Christopher P Heagney (US Naval Air Systems Command, USA)

Design & Production Verification Lifecycle Of An EW Receiver Line Replaceable Unit (LRU) According To The Military Standards.....338

Sabiha Hande Koru (ASELSAN, Turkey)

Zafer Savas (ASELSAN Inc. & ASELSAN Inc., Turkey)

Automated Multi-Channel DC-Biased Burn-in Test System using Hall Effect Current Sensor.....343

Kagan Tanaydin (Aselsan, Turkey)

Ridvan Surbahanli (Aselsan, Turkey)

3B2: Test & Support Management II

10:30-12:00

Room: Baltimore 3

Session Chair: Michael J Dewey (Marvin Test Solutions, USA)

Optimizing Regression Testing of Software for the Consolidated Automated Support System348

Christopher J Sparr (NAVAIR, USA)

Robert Fox (NAVAIR, USA)

Yun Song (NAVAIR, USA)

Management of Test Utilization, Optimization, and Health through Real-Time Data353

Duane Lowenstein (Keysight Technologies, USA)

Charlie Slater (Keysight, USA)

Measuring Manufacturing Test Data Analysis Quality359

Kevin Lynch (Raytheon, USA)

Andrew Burkhardt (Raytheon, USA)

Sheila Berryman (Raytheon, USA)

Ashley Brio (Milwaukee Bucks National Basketball Association, USA)

Susan Ferkau (Raytheon, USA)

Gloria Hubner (Raytheon, USA)

Susan Mittman (Raytheon, USA)

Kathy Sonderer (Raytheon, USA)